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Term:	<input type="text" value="l2 and L3"/>
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Display:	<input type="text" value="20"/>	Documents in Display Format:	<input type="text" value="-"/>	Starting with Number	<input type="text" value="1"/>
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result set

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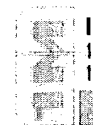
<u>L5</u>	L2 not l4	48	<u>L5</u>
<u>L4</u>	l2 and L3	35	<u>L4</u>
<u>L3</u>	707/\$.ccls.	22448	<u>L3</u>
<u>L2</u>	L1 and disambiguate\$	83	<u>L2</u>
<u>L1</u>	classif\$ near3 (term\$ or keyword or vocabulary or categor\$)	14279	<u>L1</u>

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